3GPP TSG-T Meeting #11 Palm Springs, USA , 14-16 March, 2001 Agenda Item:

Source: ARIB

Title: TS34.121 CR for regional requirements on Test Tolerance

Document for: Discussion and Approval

In TSG-RAN#11 meeting in Palm Springs (Mar 2001), a proposal [1] on how to handle regional requirements in test tolerances section of TS25.141 was discussed. It was originally based on the CR proposed at RAN-WG4#15 meeting [2]. At this stage, ARIB believes that it is worthwhile and necessary for TSG-T/RAN to make substantial discussion on this issue and realizes that there is room to achieve common understanding and adequate resolution. Consensus obtained thorough discussion in the floor at TSG-RAN#11 as well as successive offline discussion seemed to be that TSG RAN needed to take two actions to solve the issue. One is that PCG should be asked for general guidance for such a particular case that how to resolve such tentative inconsistency between 3GPP specifications and regulations needs to be considered. Another is that an adequate text is to be added to 4.7 Regional requirements of TS25.141 and TS34.121 as well. Taking into account comments from TSG-RAN discussion, attached CR for TS34.121 has been drafted and is proposed for approval.

Reference

- [1] RP-010083," Regional requirements on Test Tolerances ",ARIB
- [2] R4-010225," CR for Regional requirements on Test Tolerances (Rev2)",ARIB

CHANGE REQUEST													
*	34.	.121	CR NU	IM	₩ r	ev	- #	Сι	ırrent ve	ersion:	3.3.) [#]	
For <u>HELP</u> on using this form, see bottom of this page or look at the pop-up text over the % symbols.													
Proposed change affects: (U)SIM ME/UE X Radio Access Network Core Network ■													
Title: 第	Reç	gional r	requiremer	nts on Tes	st Tole	rance)						
Source: #	ARI	IB											
Work item code: 第									Date:	ж <mark>03</mark>	3.15.200°	1	
Category: Ж	F							Re	elease:	ж R	99		
Reason for change	Detai be fo	F (esse A (corr B (Add C (Fun D (Edit illed exp bund in 3	the following ential correct responds to dition of feature to distribute the correct of the corr	a correction a correction for the above 1.900. apanese n of TS34 n-zero tes on as a modern as a correction of the corre	regularitely tolerate all	e) ories of ations they of ances the cloof factors	could do not s. Altho hanges t, before	only reflectingly, s in Tre all	2 R96 R97 R98 R99 REL-4 REL-5 be base ct latest Japane TS34.12 the cha	(GS) (Re) (Re) (Re) (Re) (Re) (Re) (Re) (Test I	requirem gulations ill take ce are incor	2) 6) 7) 8) 9) uiremeents" have ertain	ents" which to be
		confu allow neces	non possibusion nor ming "tentations sary.	nisunderst ve applica	tandin ation o	g causof 'test	sed by t requir	this reme	inconsis ents' with	stency n 'zero	, clear in test tole	dication rance	'" is
Summary of chang	i e: ૠ	zero	dicate that may be ap on-zero tes	plied prov	isiona/	ally as	region	nal re	quireme	ent in .	Japan by	the ti	
Consequences if not approved:	¥	zero 1 3GPF	e meantime test tolerar P and the r nformance	nce", there	e will b	oe inc	onsiste	ency	betweer	n test	requirem	ents i	n
Clauses affected:	ж	Anne	x-F										
Other specs Affected:	* [Te	her core specifica M Specific	ations	ons	ж							
Other comments:	¥	each	oroposed s region refl I.121.										n

Annex F (normative): General test conditions and declarations

The requirements of this clause apply to all tests in the present document, when applicable.

Many of the tests in the present document measure a parameter relative to a value which is not fully specified in the UE specifications. For these tests, the conformance requirement is determined relative to a nominal value specified by the manufacturer.

When specified in a test, the manufacturer shall declare the nominal value of a parameter, or whether an option is supported.

In order to be consistent with industry practise, the shared risk principle shall be used for all tests. It may be decided to relax the core specification value by a certain relaxation value (hereby named "Test Tolerance") that should be evaluated on a case per case basis taking into account different factors such as test equipment uncertainty, mismatch, and criticality for system performance.

In all the relevant subclauses in this clause all Bit Error Ratio (BER), Block Error Ratio (BLER), False transmit format Detection Ratio (FDR) measurements shall be carried out according to the general rules for statistical testing in annex F.4.

Note: Until the time the non-zero test tolerances are reflected in the Japanese regulations, shared risk against core specification value with test tolerance of zero may be applied provisionally for the following minimum requirements as regional requirement in Japan. This note should be reviewed to check its necessity every TSG-T meeting.

- 5.2 Maximum output power
- 5.3 Frequency error
- 5.4.1 Open Loop Power Control in the Uplink
- 5.4.2 Inner Loop Power Control in the uplink
- 5.5.1 Transmit off power
- 5.10 Spectrum Emission Mask
- 6.2 Receiver Sensitivity Level
- 6.4 Adjacent Channel Selectivity
- 6.7 Intermodulation Characteristics
- 5.13.2 Peak code domain error